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• ,	Q 61 30 8		Page <u>1</u> of <u>2</u>
Form PTO-1449 U.S. DEPARTMENT OF COPATENT AND TRADEMA INFORMATION DISCLOSE STATEMENT BY APPLICATION. (Use several sheets if necessary)	URE	Atty. Docket No. 98095DIV3	Serial No. 10/008,653
		Applicant Gonzalez et al.	
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